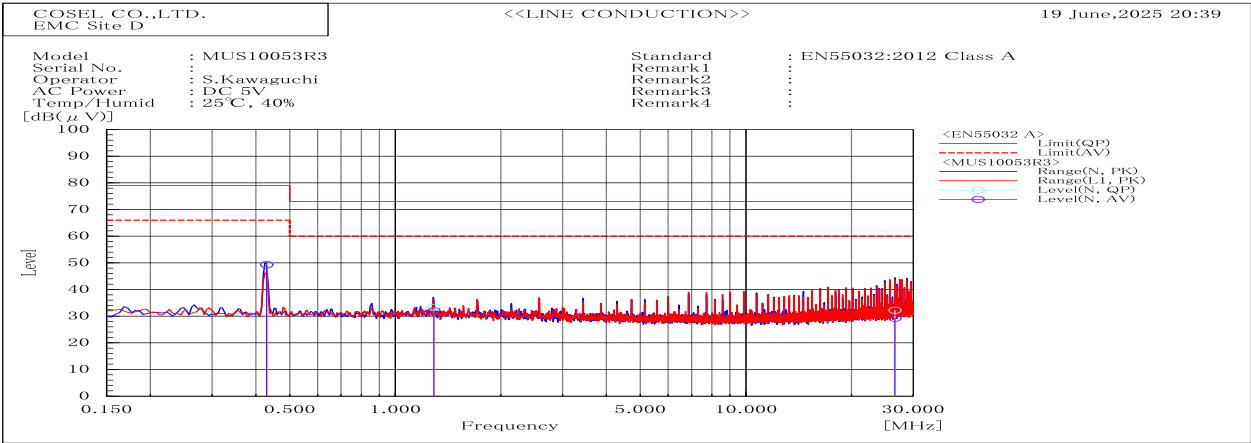
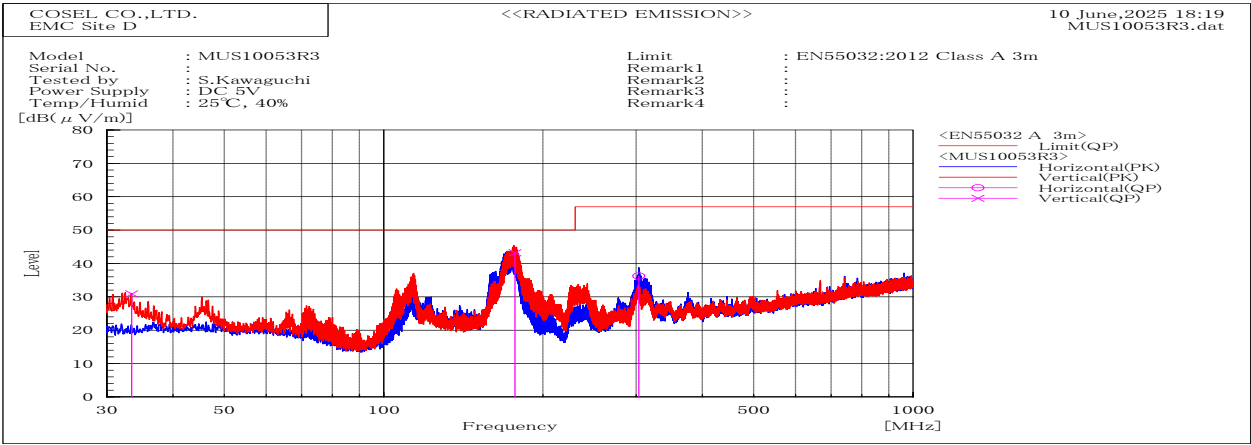


DATA SHEET		Date	19-Jun-25
Model	MUS10053R3	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Kawaguchi



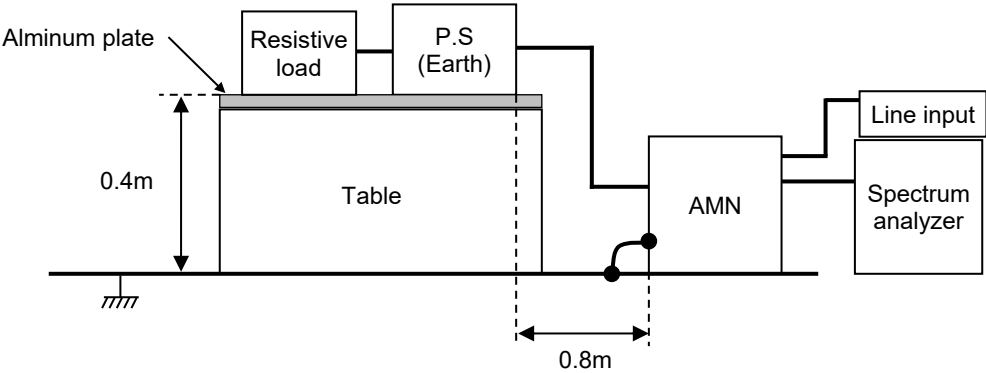
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.43	N	49.5	49.3	79	66	29.5	16.7	Pass	
1.288	N	33.3	32	73	60	39.7	28	Pass	
26.622	N	32.2	29.3	73	60	40.8	30.7	Pass	



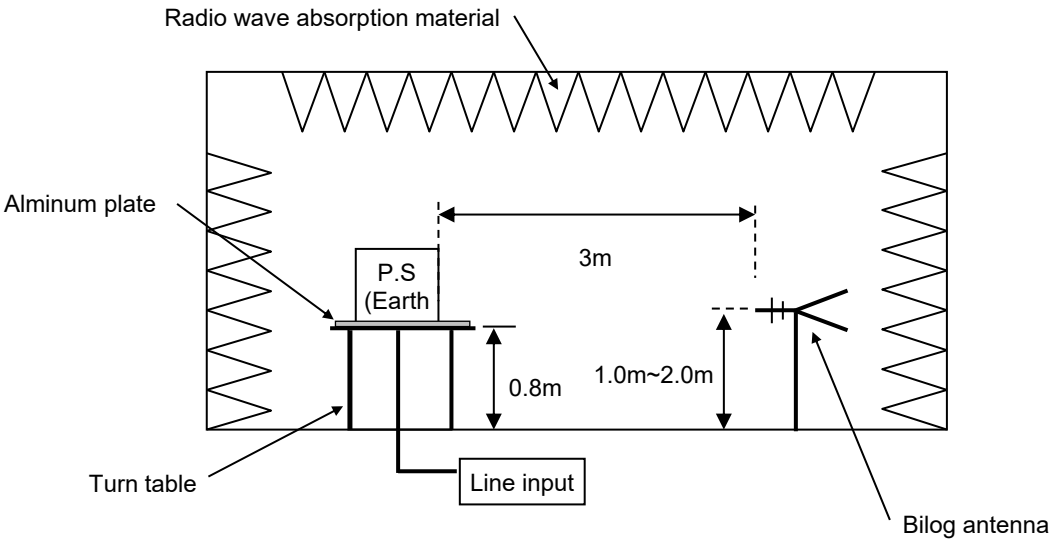
Frequency MHz	Polarization	Stability	Level dB(uV/m)	Limit dB(uV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP	QP				
176.976	V	Stable	43.2	50	6.8	Pass	100.2	0	
33.429	V	Stable	30.9	50	19.1	Pass	100.2	350.8	
303.363	H	Stable	36.2	57	20.8	Pass	110.1	246.3	

DATA SHEET		Date	19-Jun-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Kawaguchi

1. Line conduction



2. Radiated emission



Conditions

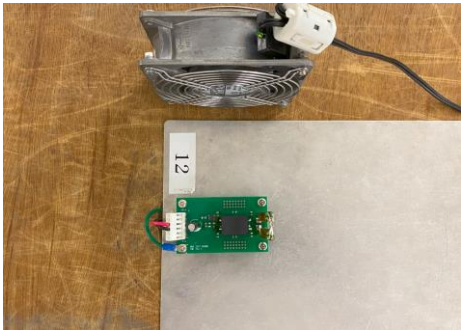
Test : EMI
 Model Name: MUS10□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

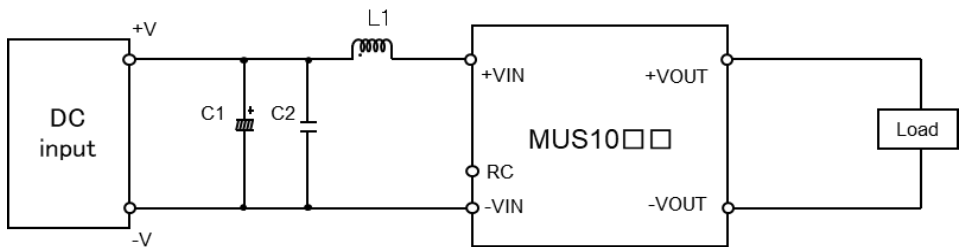


Fig.1 MUS10□□ Testing circuitry

C1 :	MUS1005□	25V 1500 μ F	Electric capacitor (LXZseries NIPPON CHEMI-CON)
	MUS1012□	50V 100 μ F	Electric capacitor (UPWseries NICHICON)
	MUS1024□	—	
	MUS1048□	—	
C2 :	MUS1005□	16V 22 μ F	Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING)
	MUS1012□	25V 10 μ F	Ceramic capacitor (CM316X7R106K25AT KYOCERA)
	MUS1024□	50V 4.7 μ F	Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MUS1048□	100V 2.2 μ F	Ceramic capacitor (C3216X7S2A225KT TDK)
L1 :	MUS1005□	5000mA 2.2 μ H	Inductor(LQH5BPN2R2N38 MURATA MANUFACTURING)
	MUS1012□	3500mA 4.7 μ H	Inductor(LQH5BPN4R7N38 MURATA MANUFACTURING)
	MUS1024□	1600mA 22 μ H	Inductor(LQH5BPN220M38 MURATA MANUFACTURING)
	MUS1048□	1100mA 47 μ H	Inductor(LQH5BPN470M38 MURATA MANUFACTURING)